Test Report

No.: EKR23701858 Date: 02-Aug-2023

NXP SEMICONDUCTORS
HIGH TECH CAMPUS 60, 5656AG EINDHOVEN, THE NETHERLANDS

The following sample(s) was/were submitted and identified by the applicant as:

Sample Submitted By : NXP SEMICONDUCTORS NETHERLANDS B.V.
Sample Name : OAK HILL PB-FRIT WAFER

==========

Sample Receiving Date : 25-Jul-2023
Testing Period : 25-Jul-2023 to 02-Aug-2023

Test Requested :
(1) As specified by client, with reference to RoHS 2011/65/EU Annex II and amending Directive (EU) 2015/863 to determine Cadmium, Lead, Mercury, Cr(VI), PBBs, PBDEs, DBP, BBP, DEHP, DIBP contents in the submitted sample(s).
(2) Please refer to next pages for the other item(s).

Test Results : Please refer to following pages.

Ray Chang, Ph.D./Department Manager
Signed for and on behalf of
SGS TAIWAN LTD.
Chemical Laboratory-Kaohsiung

CHECK REPORT
PIN CODE: 4CB05D42

NXP SEMICONDUCTORS
HIGH TECH CAMPUS 60, 5656AG EINDHOVEN, THE NETHERLANDS

Test Part Description

No.1 : WAFER

Test Result(s)

Test Item(s)	Method	Unit	MDL	Result
				No.1
Cadmium (Cd)	With reference to IEC 62321-5: 2013, analysis was performed by ICP-OES.	mg/kg	2	n.d.
Lead (Pb)		mg/kg	2	10500
Mercury (Hg)	With reference to IEC 62321-4: 2013+ AMD1: 2017, analysis was performed by ICP-OES.	mg/kg	2	n.d.
Hexavalent Chromium Cr(VI)	With reference to IEC 62321-7-2: 2017, analysis was performed by UV-VIS.	mg/kg	8	n.d.
Monobromobiphenyl	With reference to IEC 62321-6: 2015, analysis was performed by GC/MS.	mg/kg	5	n.d.
Dibromobiphenyl		mg/kg	5	n.d.
Tribromobiphenyl		mg/kg	5	n.d.
Tetrabromobiphenyl		mg/kg	5	n.d.
Pentabromobiphenyl		mg/kg	5	n.d.
Hexabromobiphenyl		mg/kg	5	n.d.
Heptabromobiphenyl		mg/kg	5	n.d.
Octabromobiphenyl		mg/kg	5	n.d.
Nonabromobiphenyl		mg/kg	5	n.d.
Decabromobiphenyl		mg/kg	5	n.d.
Sum of PBBs		mg/kg	-	n.d.
Monobromodiphenyl ether		mg/kg	5	n.d.
Dibromodiphenyl ether		mg/kg	5	n.d.
Tribromodiphenyl ether		mg/kg	5	n.d.
Tetrabromodiphenyl ether		mg/kg	5	n.d.
Pentabromodiphenyl ether		mg/kg	5	n.d.
Hexabromodiphenyl ether		mg/kg	5	n.d.
Heptabromodiphenyl ether		mg/kg	5	n.d.
Octabromodiphenyl ether		mg/kg	5	n.d.
Nonabromodiphenyl ether		mg/kg	5	n.d.
Decabromodiphenyl ether		mg/kg	5	n.d.
Sum of PBDEs		mg/kg	-	n.d.

NXP SEMICONDUCTORS
HIGH TECH CAMPUS 60, 5656AG EINDHOVEN, THE NETHERLANDS

Test Item(s)	Method	Unit	MDL	Result
				No.1
Butyl benzyl phthalate (BBP)	With reference to IEC 62321-8: 2017, analysis was performed by GC/MS.	mg/kg	50	n.d.
Dibutyl phthalate (DBP)	With reference to IEC 62321-8: 2017, analysis was performed by GC/MS.	mg/kg	50	n.d.
Diisobutyl phthalate (DIBP)	With reference to IEC 62321-8: 2017, analysis was performed by GC/MS.	mg/kg	50	n.d.
Di-(2-ethylhexyl) phthalate (DEHP)	With reference to IEC 62321-8: 2017, analysis was performed by GC/MS.	mg/kg	50	n.d.
Diisononyl phthalate (DINP) (CAS No.: 28553-12-0, 68515-48-0)	With reference to IEC 62321-8: 2017, analysis was performed by GC/MS.	mg/kg	50	n.d.
Diisodecyl phthalate (DIDP) (CAS No.: 26761-40-0, 68515-49-1)	With reference to IEC 62321-8: 2017, analysis was performed by GC/MS.	mg/kg	50	n.d.
Di-n-octyl phthalate (DNOP) (CAS No.: 117-84-0)	With reference to IEC 62321-8: 2017, analysis was performed by GC/MS.	mg/kg	50	n.d.
Di-n-pentyl phthalate (DNPP) (CAS No.: 131-18-0)	With reference to IEC 62321-8: 2017, analysis was performed by GC/MS.	mg/kg	50	n.d.
Antimony (Sb) (CAS No.: 7440-36-0)	With reference to US EPA 3052: 1996, analysis was performed by ICP-OES.	mg/kg	2	n.d.
Beryllium (Be) (CAS No.: 7440-41-7)	With reference to US EPA 3052: 1996, analysis was performed by ICP-OES.	mg/kg	2	n.d.
Arsenic (As) (CAS No.: 7440-38-2)	With reference to US EPA 3052: 1996, analysis was performed by ICP-OES.	mg/kg	2	n.d.
Fluorine (F) (CAS No.: 14762-94-8)	With reference to BS EN 14582: 2016, analysis was performed by IC.	mg/kg	50	n.d.
Chlorine (Cl) (CAS No.: 22537-15-1)	With reference to BS EN 14582: 2016, analysis was performed by IC.	mg/kg	50	n.d.
Bromine (Br) (CAS No.: 10097-32-2)	With reference to BS EN 14582: 2016, analysis was performed by IC.	mg/kg	50	n.d.
Iodine (I) (CAS No.: 14362-44-8)	With reference to BS EN 14582: 2016, analysis was performed by IC.	mg/kg	50	n.d.

NXP SEMICONDUCTORS
HIGH TECH CAMPUS 60, 5656AG EINDHOVEN, THE NETHERLANDS

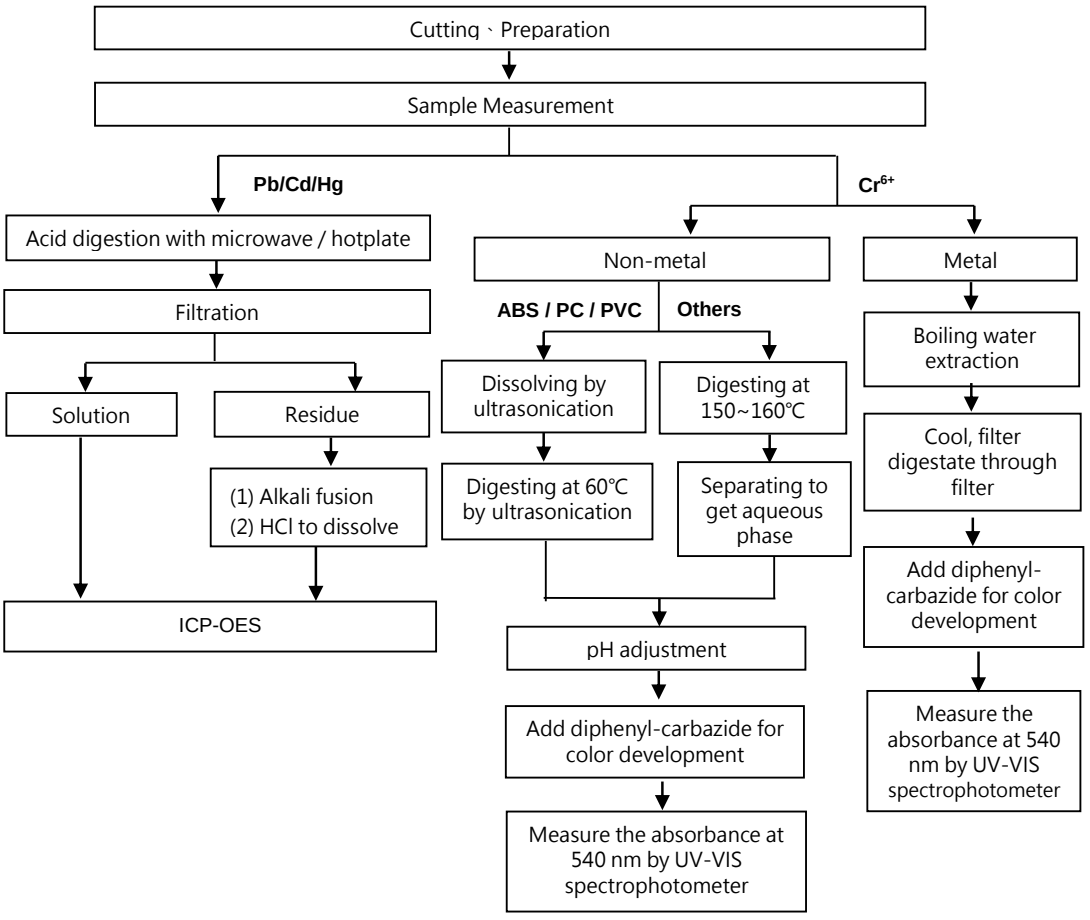
Note：

1. mg/kg = ppm；0.1wt% = 0.1% = 1000ppm
2. MDL = Method Detection Limit
3. n.d. = Not Detected (Less than MDL)
4. "-" = Not Regulated

NXP SEMICONDUCTORS
HIGH TECH CAMPUS 60, 5656AG EINDHOVEN, THE NETHERLANDS

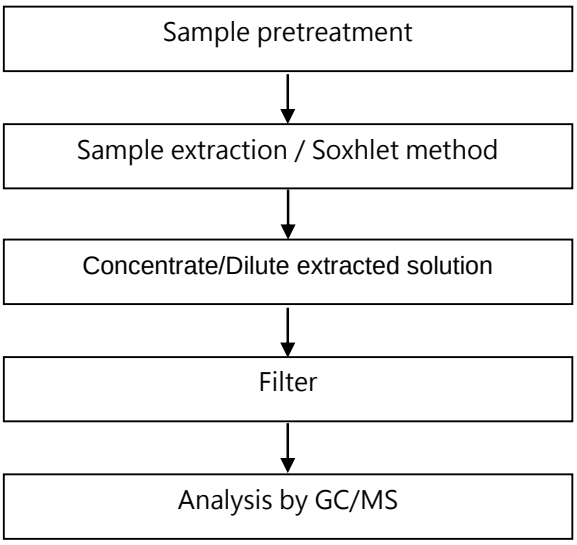
Analytical flow chart of Heavy Metal

These samples were dissolved totally by pre-conditioning method according to below flow chart.
(Cr^{6+} test method excluded)



NXP SEMICONDUCTORS
HIGH TECH CAMPUS 60, 5656AG EINDHOVEN, THE NETHERLANDS

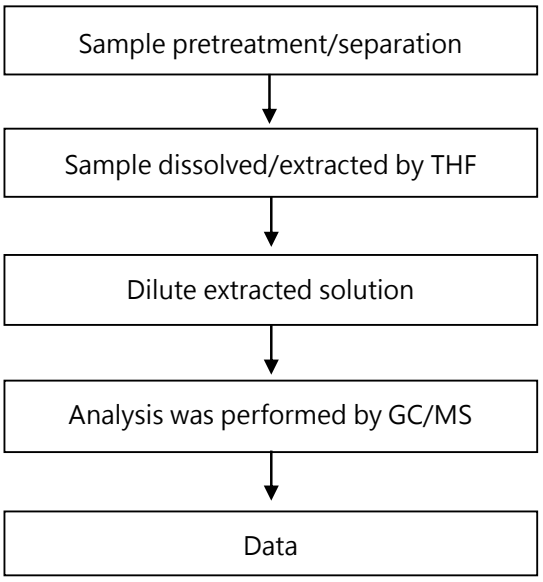
PBB/PBDE analytical FLOW CHART



NXP SEMICONDUCTORS
HIGH TECH CAMPUS 60, 5656AG EINDHOVEN, THE NETHERLANDS

Analytical flow chart of phthalate content

【Test method: IEC 62321-8】

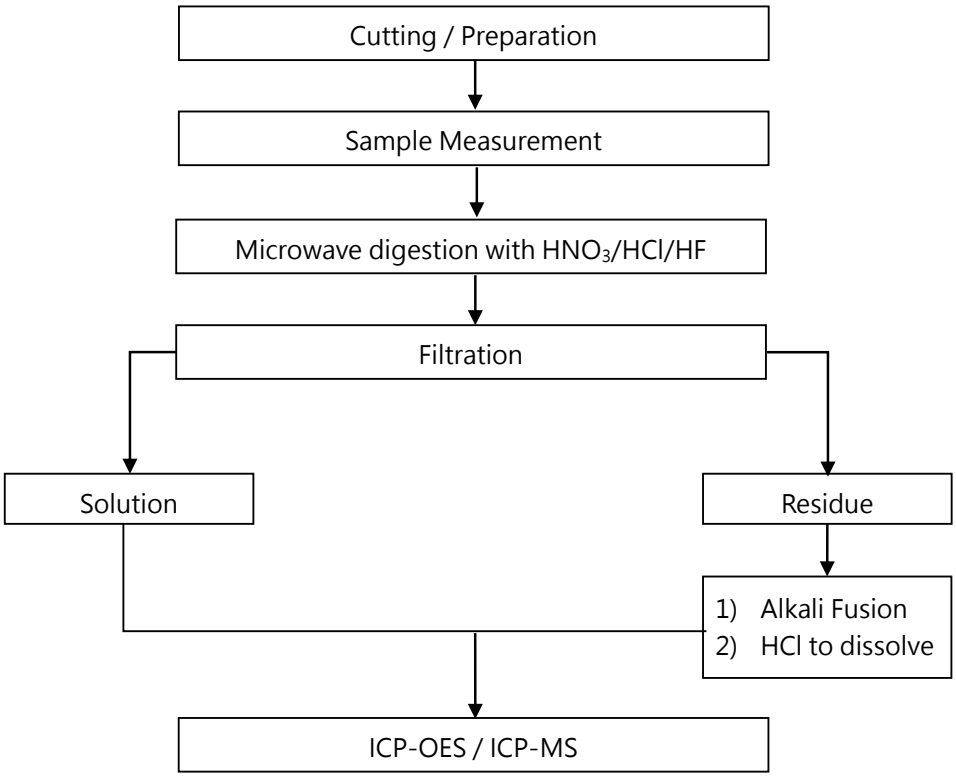


NXP SEMICONDUCTORS
HIGH TECH CAMPUS 60, 5656AG EINDHOVEN, THE NETHERLANDS

Analytical flow chart of Elements (Heavy metal included)

These samples were dissolved totally by pre-conditioning method according to below flow chart.

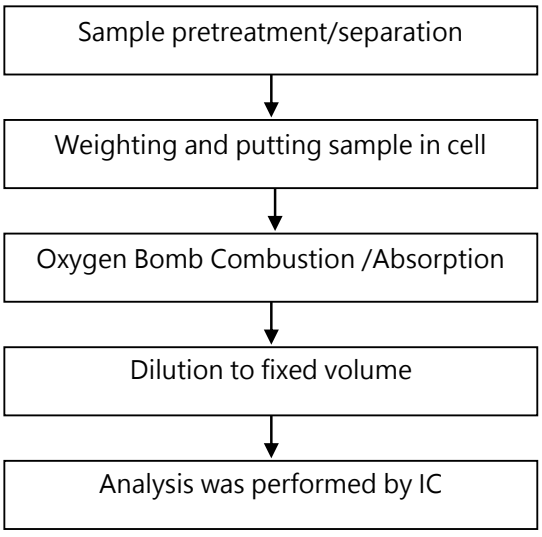
【Reference method：US EPA 3051、US EPA 3052】



* US EPA 3051 method does not add HF.

NXP SEMICONDUCTORS
HIGH TECH CAMPUS 60, 5656AG EINDHOVEN, THE NETHERLANDS

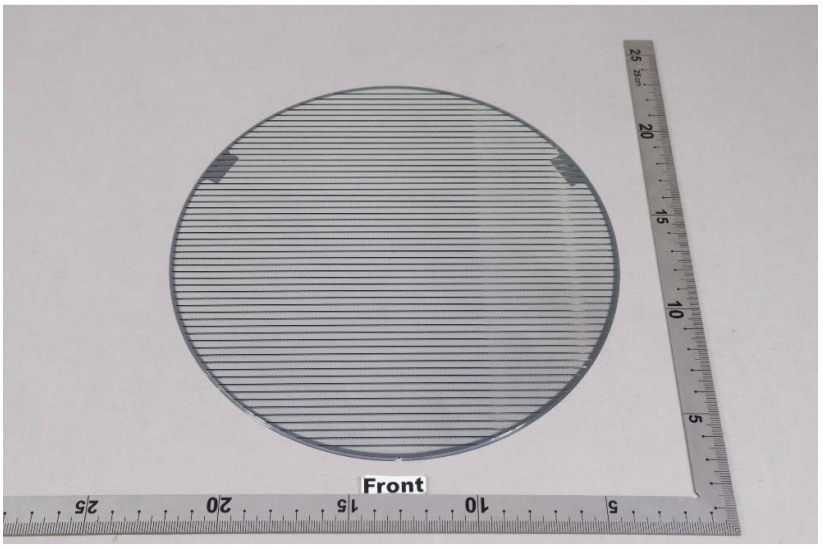
Analytical flow chart of Halogen



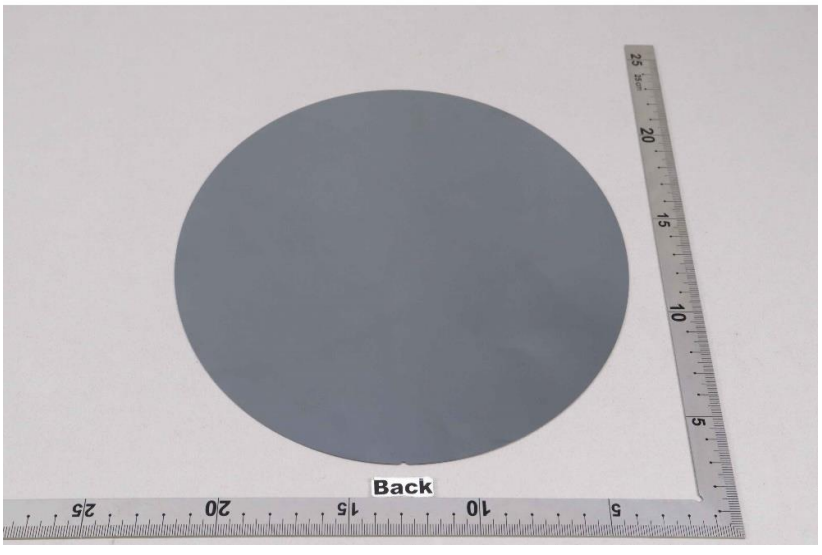
NXP SEMICONDUCTORS
HIGH TECH CAMPUS 60, 5656AG EINDHOVEN, THE NETHERLANDS

* The tested sample / part is marked by an arrow if it's shown on the photo. *

EKR23701858



EKR23701858



** End of Report **